

# Supplementary materials for

## A Highly Thermostable In<sub>2</sub>O<sub>3</sub>/ITO Thin Film Thermocouple Prepared via Screen Printing for High Temperature Measurements

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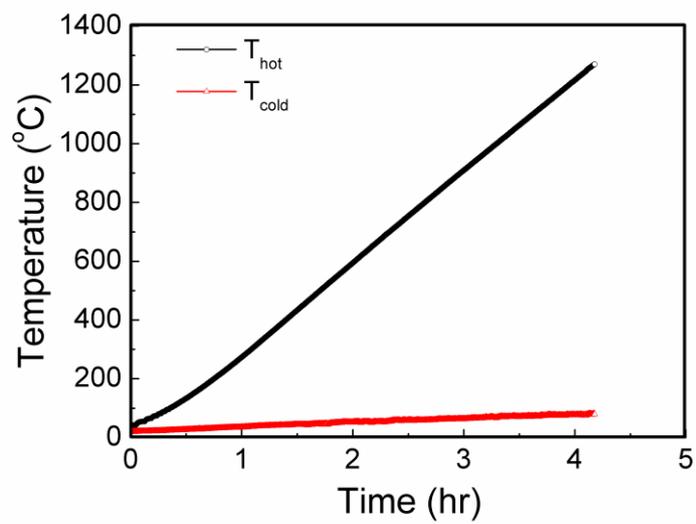
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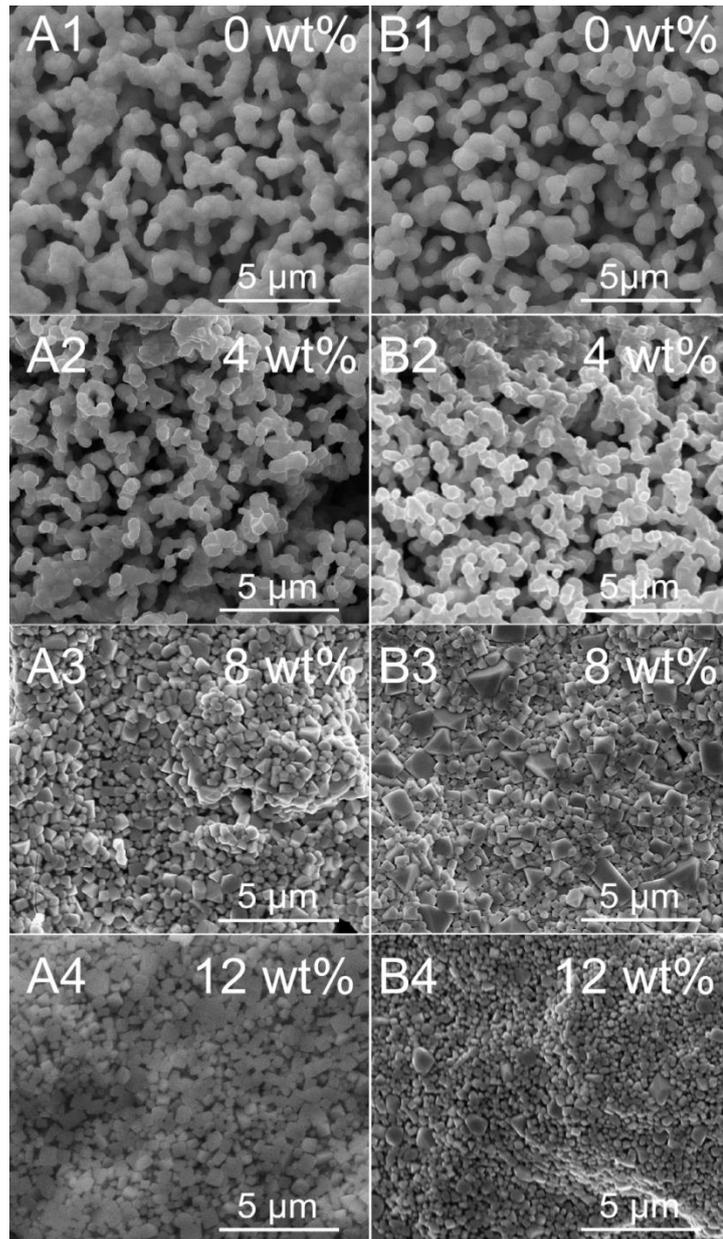
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**Figure S1.** The temperature changes of the cold and hot junctions of thermocouple in the heating process.



**Figure S2.** SEM surface images of ITO and In<sub>2</sub>O<sub>3</sub> films with different glass additives annealed at 1250 °C for 2 h. (A) ITO film, (B) In<sub>2</sub>O<sub>3</sub> film.